

SN54ABT863, SN74ABT863 9-BIT BUS TRANSCEIVERS WITH 3-STATE OUTPUTS

SCBS201E – FEBRUARY 1991 – REVISED JULY 1998

- State-of-the-Art **EPIC-IITM** BiCMOS Design Significantly Reduces Power Dissipation
- Typical V_{OLP} (Output Ground Bounce) < 1 V at $V_{CC} = 5$ V, $T_A = 25^\circ\text{C}$
- High-Impedance State During Power Up and Power Down
- High-Drive Outputs ($-32\text{-mA } I_{OH}$, $64\text{-mA } I_{OL}$)
- Latch-Up Performance Exceeds 500 mA Per JESD 17
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model ($C = 200$ pF, $R = 0$)
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB) Packages, and Thin Shrink Small-Outline (PW), Ceramic Chip Carriers (FK), Plastic (NT), and Ceramic (JT) DIPs

description

The 'ABT863 devices are 9-bit transceivers designed for asynchronous communication between data buses. The control-function implementation allows for maximum flexibility in timing.

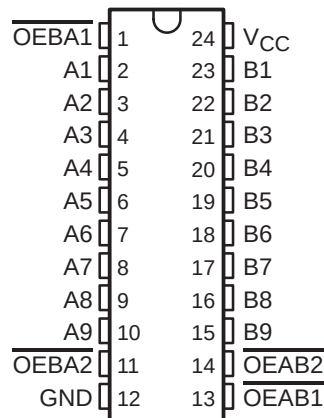
These devices allow noninverted data transmission from the A bus to the B bus or from the B bus to the A bus, depending on the logic levels at the output-enable ($\overline{\text{OEAB}}$ and $\overline{\text{OEBA}}$) inputs.

The outputs are in the high-impedance state during power up and power down. The outputs remain in the high-impedance state while the device is powered down.

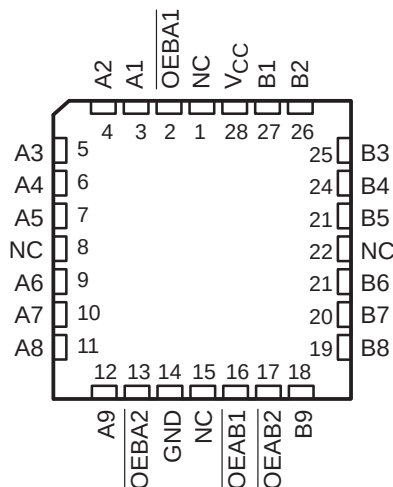
When V_{CC} is between 0 and 2.1 V, the device is in the high-impedance state during power up or power down. However, to ensure the high-impedance state above 2.1 V, $\overline{\text{OE}}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54ABT863 is characterized for operation over the full military temperature range of -55°C to 125°C . The SN74ABT863 is characterized for operation from -40°C to 85°C .

SN54ABT863 . . . JT PACKAGE
SN74ABT863 . . . DB, DW, NT, OR PW PACKAGE
(TOP VIEW)



SN54ABT863 . . . FK PACKAGE
(TOP VIEW)



NC – No internal connection



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**TEXAS
INSTRUMENTS**

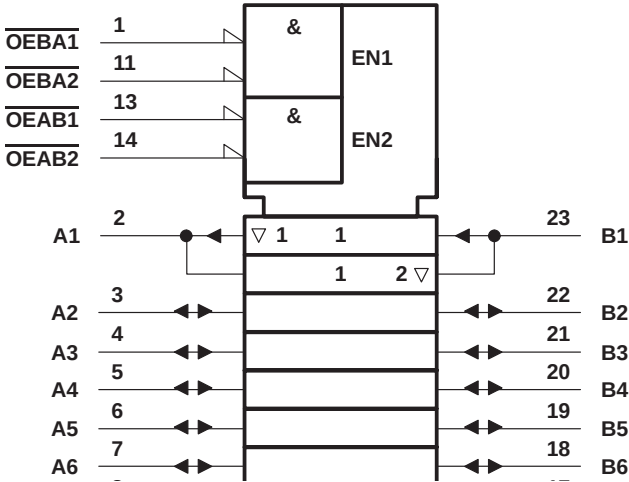
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FUNCTION TABLE

INPUTS				OPERATION
OEAB1	OEAB2	OEBA1	OEBA2	
L	L	L	L	Latch A and B
L	L	H	X	A to B
L	L	X	H	
H	X	L	L	B to A
X	H	L	L	
H	X	H	X	Isolation
H	X	X	H	
X	H	X	H	
X	H	H	X	

logic symbol†



Pin numbers shown are for the DB, DW, JT, NT, and PW packages.

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recommended operating conditions (see Note 3)

		SN54ABT863		SN74ABT863		UNIT
		MIN	MAX	MIN	MAX	
V_{CC}	Supply voltage	4.5	5.5	4.5	5.5	V
V_{IH}	High-level input voltage	2		2		V
V_{IL}	Low-level input voltage		0.8		0.8	V
V_I	Input voltage	0	V_{CC}	0	V_{CC}	V
I_{OH}	High-level output current		–24		–32	mA
I_{OL}	Low-level output current		48		64	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	Outputs enabled			5	ns/V
$\Delta t/\Delta V_{CC}$	Power-up ramp rate		200		200	$\mu s/V$
T_A	Operating free-air temperature	–55	125	–40	85	°C

NOTE 3: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	T _A = 25°C			SN54ABT863		SN74ABT863		UNIT
		MIN	TYP†	MAX	MIN	MAX	MIN	MAX	
V _{IK}	V _{CC} = 4.5 V, I _I = –18 mA			–1.2		–1.2		–1.2	V
V _{OH}	V _{CC} = 4.5 V, I _{OH} = –3 mA	2.5			2.5		2.5		V
	V _{CC} = 5 V, I _{OH} = –3 mA	3			3		3		
	V _{CC} = 4.5 V			2	2				
				2*			2		
V _{OL}	V _{CC} = 4.5 V			0.55	0.55				V
				0.55*			0.55		
V _{hys}			100						mV
I _I	Control inputs	V _{CC} = 0 to 5.5 V, V _I = V _{CC} or GND		±1	±1		±1		µA
	A or B ports	V _{CC} = 2.1 V to 5.5 V, V _I = V _{CC} or GND		±20	±20		±20		
I _{OZPU}	V _{CC} = 0 to 2.1 V, V _O = 0.5 V to 2.7 V, OE = * don't care			±50	±50**		±50		µA
I _{OZPD}	V _{CC} = 2.1 V to 0, V _O = 0.5 V to 2.7 V, OE = * don't care			±50	±50**		±50		µA
I _{OZH} ‡	V _{CC} = 2.1 V to 5.5 V, V _O = 2.7 V, OE ≥ 2 V			10	10		10		µA
I _{OZL} ‡	V _{CC} = 2.1 V to 5.5 V, V _O = 0.5 V, OE ≥ 2 V			–10	–10		–10		µA
I _{off}	V _{CC} = 0, V _I or V _O ≤ 4.5 V			±100*			±100		µA
I _{CEX}	V _{CC} = 5.5 V, V _O = 5.5 V	Outputs high		50	50		50		µA
I _O §	V _{CC} = 5.5 V, V _O = 2.5 V	–50	–100	–225	–50	–225	–50	–225	mA
I _{CC}	A or B ports	V _{CC} = 5.5 V, I _O = 0, V _I = V _{CC} or GND	Outputs high		1	250	250	250	µA
			Outputs low		24	30	38	38	mA
			Outputs disabled		0.5	250	250	250	µA
ΔI _{CC} ¶	Data inputs	V _{CC} = 5.5 V, One input at 3.4 V, Other inputs at V _{CC} or GND	Outputs enabled		1.5		1.5		mA
			Outputs disabled		0.05		0.05		
	Control inputs	V _{CC} = 5.5 V, One input at 3.4 V, Other inputs at V _{CC} or GND		1.5		1.5		1.5	
C _i	Control inputs	V _I = 2.5 V or 0.5 V		4					pF
C _{io}	A or B ports	V _O = 2.5 V or 0.5 V		7					pF

* On products compliant to MIL-PRF-38535, this parameter does not apply.

** On products compliant to MIL-PRF-38535, this parameter is not production tested.

† All typical values are at V_{CC} = 5 V.

‡ The parameters I_{OZH} and I_{OZL} include the input leakage current.

§ Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

¶ This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.

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switching characteristics over recommended ranges of supply voltage and operating free-air temperature, $C_L = 50$ pF (unless otherwise noted) (see Figure 1)

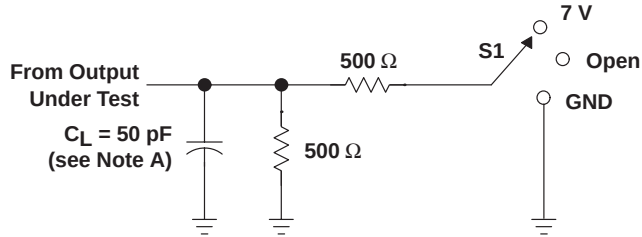
PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 5$ V, $T_A = 25^\circ\text{C}$			SN54ABT863		SN74ABT863		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t_{PLH}	A or B	B or A	1	2.6	4.1	1	7	1	5.7	ns
t_{PHL}			1	2.3	3.3	1	3.9	1	3.9	
t_{PZH}	$\overline{OEAB}$ or $\overline{OEBA}$	B or A	1	3.2	4.3	1	5.4	1	5.5	ns
t_{PZL}			1	3.3	4.4	1	5.5	1	5.4	
t_{PHZ}	$\overline{OEAB}$ or $\overline{OEBA}$	B or A	2.5	4.8	6	2.5	6.8	2.5	6.7	ns
t_{PLZ}			1.5	4.4	5.9	1.5	7.8	1.5	6.9	

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PARAMETER MEASUREMENT INFORMATION



TEST	S1
t_{PLH}/t_{PHL}	Open
t_{PLZ}/t_{PZL}	7 V
t_{PHZ}/t_{PZH}	Open

LOAD CIRCUIT

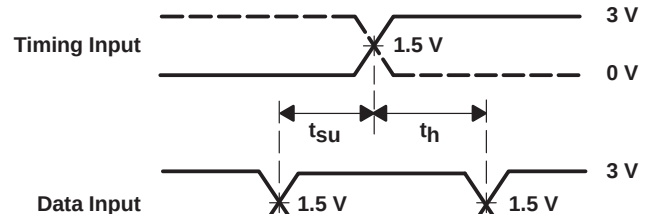
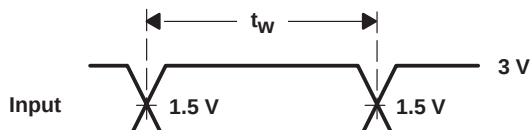


Figure 1. Load Circuit and Voltage Waveforms

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